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 Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

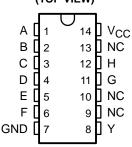
These devices contain an 8-input positive-NAND gate and perform the following Boolean functions in positive logic:

 $Y = \overline{A \bullet B \bullet C \bullet D \bullet E \bullet F \bullet G \bullet H}$ $Y = \overline{A + \overline{B} + \overline{C} + \overline{D} + \overline{E} + \overline{F} + \overline{G} + \overline{H}}$

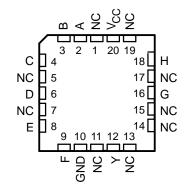
The SN54ALS30A and SN54AS30 are characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ALS30A and SN74AS30 are characterized for operation from 0°C to 70°C.

FUNCTION TABLE							
INPUTS A-H	OUTPUT Y						
All inputs H	L						
One or more inputs L	Н						

SN54ALS30A, SN54AS30 ... J PACKAGE SN74ALS30A, SN74AS30 ... D OR N PACKAGE (TOP VIEW)

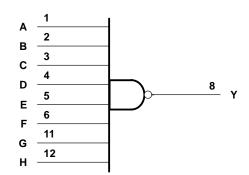


SN54ALS30A, SN54AS30 . . . FK PACKAGE (TOP VIEW)

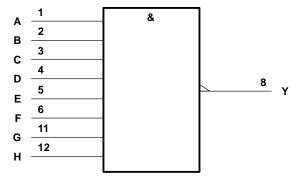


NC - No internal connection

logic diagram (positive logic)



logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Operating free-air temperature range, TA: SN54ALS	30A –55°C to 125°C 30A
	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54ALS30A SN74ALS30A MIN NOM MAX MIN NOM MA		SN74ALS30A			UNIT	
				MAX	UNIT			
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
Ma	Low-level input voltage			0.8‡			0.8	V
VIL				0.7§				v
ЮН	High-level output current			-0.4			-0.4	mA
IOL	Low-level output current			4			8	mA
TA	Operating free-air temperature	-55		125	0		70	°C

[‡] Applies over temperature range – 55°C to 70°C

§ Applies over temperature range 70°C to 125°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEAT O		SN	54ALS3)A	SN	74ALS3	0A	UNIT
PARAMETER	IESI G	TEST CONDITIONS		τγρ¶	MAX	MIN	τγρ¶	MAX	UNIT
VIK	V _{CC} = 4.5 V,	lj = -18 mA			-1.5			-1.5	V
VOH	V_{CC} = 4.5 V to 5.5 V,	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2	2		V _{CC} -2	2		V
VoL		$I_{OL} = 4 \text{ mA}$		0.25	0.4		0.25	0.4	V
VOL	V _{CC} = 4.5 V	I _{OL} = 8 mA					0.35	0.5	v
lį	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
ΙΗ	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μA
١ _{١L}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.1			-0.1	mA
IO#	V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
ICCH	V _{CC} = 5.5 V,	$V_{I} = 0$		0.22	0.36		0.22	0.36	mA
ICCL	V _{CC} = 5.5 V,	V _I = 4.5 V		0.54	0.9		0.54	0.9	mA

¶ All typical values are at V_{CC} = 5 V, $T_A = 25^{\circ}C$.

The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.



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switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	ТО (ОИТРИТ)	V _C C _L R _L T _A SN54AI	UNIT			
			MIN	MAX	MIN	MAX	
^t PLH	A, B, C, D, E, F, G, or H	v	3	15	3	10	
^t PHL	A, B, C, D, E, F, G, O H		3	15	3	12	ns

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage, V _{CC} Input voltage, V _I	
Operating free-air temperature range, T _A : SN54AS30	-55°C to 125°C
SN74AS30	0°C to 70°C
Storage temperature range	-65°C to 150°C

Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54AS30		SN74AS30			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
ЮН	High-level output current			-2			-2	mA
IOL	Low-level output current			20			20	mA
TA	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		SN54AS30			S	UNIT		
PARAMETER	TEST C	TEST CONDITIONS		TYP§	MAX	MIN	TYP§	MAX	UNIT
VIK	V _{CC} = 4.5 V,	lj = –18 mA			-1.2			-1.2	V
VOH	V_{CC} = 4.5 V to 5.5 V,	I _{OH} = -2 mA	V _{CC} -2	2		V _{CC} -2	2		V
VOL	V _{CC} = 4.5 V,	I _{OL} = 20 mA		0.35	0.5		0.35	0.5	V
lj	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
ЧН	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μA
١ _{١L}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.5			-0.5	mA
۱ _О ¶	V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	-30		-112	mA
ІССН	V _{CC} = 5.5 V,	$V_{I} = 0$		0.9	1.5		0.9	1.5	mA
ICCL	V _{CC} = 5.5 V,	V _I = 4.5 V		3	4.9		3	4.9	mA

§ All typical values are at V_{CC} = 5 V, T_A = 25° C.

The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

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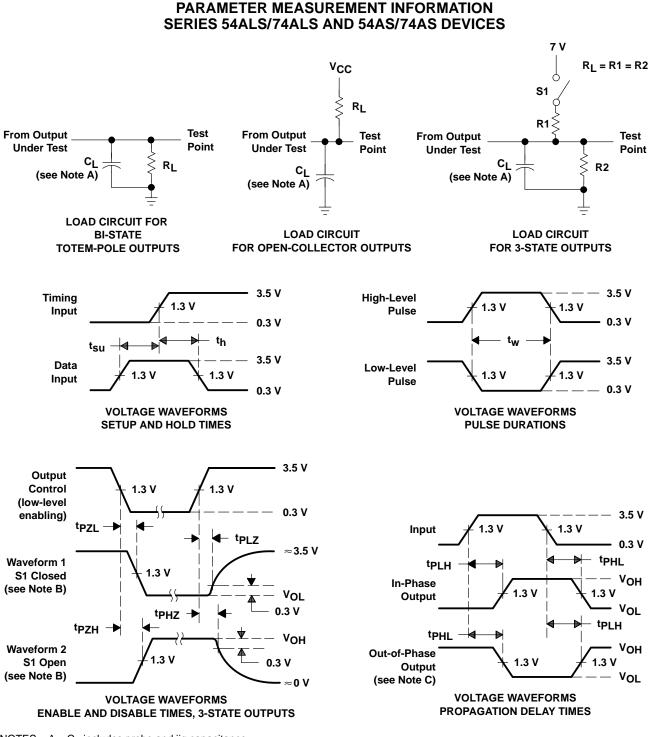
switching characteristics (see Figure 1)

	PARAMETER	FROM (INPUT)	то (оитрит)	V _C C _L R _L T _A SN54	UNIT			
				MIN	MAX	SN74/ MIN	MAX	
	^t PLH		v	1	5.5	1	5	
	^t PHL	A, B, C, D, E, F, G, or H	ſ	1	5	1	4.5	ns

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, t_{f} = t_{f} = 2 ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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